# Using Charm Flavour tagger with  $D^0 \rightarrow K_{\rm S} K_{\rm S}$

Sanjeeda Bharati Das<sup>1</sup>, Kavita Lalwani<sup>1</sup>, Angelo Di Canto<sup>2</sup>  $M$ NIT Jaipur<sup>1</sup>, BNL, USA<sup>2</sup>

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# **Today's talk**

- Goal: Measurement of CP Asymmetry in  $D^0 \rightarrow K_{\rm S} K_{\rm S}$  .
- Explore the prospect of using Charm Flavour Tagger (CFT):
	- Data Sample & Selection Criteria
	- Physics Motivation for CFT
	- **Results:** Measurement of CFT Metrics with 200fb<sup>-1</sup> for prompt  $D^0 \rightarrow K_S K_S$

# **Data Sample & Selection Criteria**

#### **Trial Sample & Software version:**

- MC15ri,  $200fb^{-1}$
- light-2207-bengal

### **Selection Criteria :**

- *For charged tracks:*
	- *thetaInCDCAcceptance*
	- *dr<0.5 && abs(dz)<2*
	- *[nSVDHits>0] and [nCDCHits>20]*
- *K\_S0:merged is used*
	- *KS\_significanceOfDistance >20*
- For  $D^0$ :
	- *Dz\_p\_CMS > 2.5 GeV/c*
	- *1.7<Dz\_M<2.05 GeV/c<sup>2</sup>*

# **Physics Motivation**

Experimentally measured quantity is  $\;$  raw asymmetry ( $A_{_{\rm raw}}$ ) defined as:

$$
A_{\text{raw}} \equiv \frac{N(D^0) - N(\overline{D}^0)}{N(D^0) + N(\overline{D}^0)}
$$

$$
N(D^0) = measured yield of D^{*+} \rightarrow D^0 \pi^+, D^0 \rightarrow K_s K_s decays
$$
  

$$
N(\bar{D}^0) = measured yield of D^{*-} \rightarrow D^0 \pi^-, \bar{D}^0 \rightarrow K_s K_s decays
$$

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To measure CP Asymmetry, we need to identify (tag) the flavor the  $D^0$  meson. One can usethe charge of the slow pion  $(\pi_{\sf s})$ .



 $\rm B(D^0\to K_{\rm _S}K_{\rm _S})=~(1.321\pm0.023\pm0.036\pm0.044)~\rm x10^{4}$  *(Phys. Rev. Lett. 119 171801 )* Due to low branching fraction, it is desirable to have other flavor identifying techniques which can retain statistics in addition to efficient flavour identification.

# **Charm Flavour Tagger (CFT)**

1.**The Charm Flavour Tagger** *is a promising new tool (BELLE2-NOTE-PH-2022-044).*

2.We explore the possibility of using this new tool for our analysis.

3.We expect to considerably increase the statistics

4.CFT metrics and procedure:





### **CFT Metrics**

- The meaning of **tagging efficiency** *ε tag* and the **mistag rate** *ω* are self explanatory.
- The sensitivity of a measurement that relies on flavor tagging is directly related to the effective **tagging efficiency, or tagging power** (*ε eff tag* )

$$
\varepsilon_{tag}^{eff} = \varepsilon_{tag} r^2 = \varepsilon_{tag} (1 - 2\omega)^2, \text{ where } \qquad r = /1 - 2\omega) = \frac{R \cdot W}{R \cdot W}
$$

is a dilution factor that accounts for candidates that are not correctly tagged.

 $r = 0$  indicates that it is not possible to identify the flavor

 $r = 1$  indicates that the flavor is perfectly known.

*The tagging power represents, in essence, the effective statistical reduction of the sample size when a tagging decision is required.* 

• tagging efficiency,  $\varepsilon_{\text{tag}}$  , and the mistag rate,  $\omega$ , can be different for charm and anticharm flavors due to charge-asymmetries in detection and reconstruction and as such **Δε tag** and **Δω**

### **CFT Metrics**



#### *pred flavor* **distributions**

#### *qr* **distributions**



in a sample of signal  $D^0$  mesons:

 $(q_{true} = +1)$  is the fraction of  $D^0$  that are wrongly classified as anti-D0 ( $q_{true}$  = −1) is the fraction of anti-D<sup>0</sup> mesons wrongly classified as D0

fraction of  $D^0$  mesons that are wrongly classified as  $\overline{D}{}^0$  :

$$
\omega(q_{\text{true}} = +1) = \frac{W}{R+W} = \frac{308}{1481 + 308} = 17.22\%
$$

fraction of  $\bar{D}^0$  mesons that are wrongly classified as  $D^0$  :

$$
\omega(q_{\text{true}} = -1) = \frac{W}{R+W} = \frac{290}{1404 + 290} = 17.11\%
$$

$$
Mistag fraction (\omega) = \frac{\omega(q_{true} = +1) + \omega(q_{true} = -1)}{2} = 17.17\%
$$



### **CFT Metrics (Tagging Efficiency, Tagging Power)**

Untagged (U) =  $8$  (*qr!=qr, for no cut on qr*)

$$
U(q_{true} = +1) = 3
$$
,  $U(q_{true} = -1) = 5$ 

$$
\varepsilon_{tag}(q_{true} = +1) = \frac{R+W}{R+W+U} = \frac{1481 + 308}{1481 + 308 + 3} = 98.33\%
$$

$$
\varepsilon_{tag}(q_{true} = -1) = \frac{R+W}{R+W+U} = \frac{1404 + 290}{1404 + 290 + 5} = 99.71\%
$$

tagging efficiency = 
$$
\frac{\varepsilon_{tag}(q_{true} = +1) + \varepsilon_{tag}(q_{true} = -1)}{2} = 99.02\%
$$

tagging power =  $\varepsilon_{\it eff}$   $(1\!-\!2\,\omega)^2\!=\!42.68\,\%$ 

### **CFT Metrics**

### **CFT Metrics with 200 fb<sup>-1</sup> (** $D^0 \longrightarrow K_s K_s$ **)**



 $|qr| > 0.4$  is the optimal cut for maximum tagging power.

### **M(D<sup>0</sup> ) distributions**

#### **For prompt sample**





#### **For D\* tagged sample**





#### Prompt:  $D^0 \longrightarrow K_{s}K_{s}$ D<sup>\*</sup> tagged: D<sup>\*</sup>→D<sup>0</sup> (K<sub>s</sub>K<sub>s</sub>) $\pi_s$

### **Effect of** *|qr|* **criteria, D<sup>0</sup>Mass distributions (Prompt sample)**

 $D^0 \longrightarrow K_{s} K_{s}$ 



#### **Simulation**

### **Effect of** *|qr|* **criteria, D<sup>0</sup>Mass distributions (with D\* tagged sample)**

 $\mathbf{D}^*{\longrightarrow} \mathbf{D}^0$  ( $\mathbf{K}_{\mathrm{s}}\mathbf{K}_{\mathrm{s}}$ )π $_{\mathrm{s}}$ 

#### Simulation



### **Background in D<sup>0</sup> Mass distribution**

#### Simulation



The 'shoulder' observed in the  $M(D<sup>0</sup>)$  distribution, is consistent with a contamination from  $D_s^+$  → K<sub>s</sub> K<sub>s</sub>π<sup>+</sup> (**B** = 7.7×10<sup>-3</sup>) decay. The charged pion is used as soft pion candidate.

### **Effect of** *|qr|* **criteria, ΔM distributions (with D\* tagged sample)**

 $\mathbf{D}^*{\longrightarrow} \mathbf{D}^0$  ( $\mathbf{K}_{\mathrm{s}}\mathbf{K}_{\mathrm{s}}$ )π $_{\mathrm{s}}$ 







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### **Effect of** *|qr|* **criteria, ΔM distributions (with D\* tagged sample)**

 $\mathbf{D}^*$   $\longrightarrow$   $\mathbf{D}^0$   $(\mathbf{K}_{\mathrm{s}}\mathbf{K}_{\mathrm{s}})\pi_{\mathrm{s}}$ 

*(Signal Window: 1.845<m(D<sup>0</sup> )<1.885)*

#### Simulation





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### **Summary**

- Charm Flavour Tagger is a promising tool for flavour tagging.
- **Observed that the CFT** suppressing the backgroung in untagged sample of  $D^0 \rightarrow K_sK_s$
- G Calculated the CFT Metrics and measured a  $\sim$ 53% increase in statistics in untagged sample of  $D^0 \rightarrow K_{S}K_{S}$ .

### j **Ongoing**

Study of signal mode  $D^0 \rightarrow K_{\rm S} K_{\rm S}$  : \* Improve the fit for  $D^0 \rightarrow K_{S}K_{S}$ .

# **Backup Slides**

# **Physics Motivation**

 $D^0$  → K<sub>s</sub>K<sub>s</sub> is a Singly Cabibbo Supressed (SCS) decay which involves the interference of  $c \bar{u}$  →  $s \bar{s}$  and  $c \overline{u} \rightarrow dd$  transitions.



- Due to this interference, the CP Assymetry  $(A_{\text{cp}})$  may be enhanced to an observable level within the Standard  $\bullet$ Model.
- In Belle, the branching fraction and time-integrated  $A_{CP}$  was measured with  $D^0 \to K_{\rm s} \pi^0$  as the control sample. *(Phys. Rev. Lett. 119 171801 )*

$$
B(D^{0} \rightarrow K_{S}K_{S}) = (1.321 \pm 0.023 \pm 0.036 \pm 0.044) \times 10^{-4}
$$
  
\n
$$
A_{CP}(D^{0} \rightarrow K_{S}K_{S}) = (-0.02 \pm 1.53 \pm 0.02 \pm 0.17) \%
$$

- In this analysis, our goal is to measure the time integrated  $A_{CP}$  of  $D^0 \to K_S K_S$  using  $D^0 \to K^*K^-$  as the control 0 sample, when we reach the same statistics as Belle.
- The  $A_{CP}$  in  $D^0 \to K^+ K^-$  is measured with 0.11% precision [HFLAV] and is expected to improve. *https://hflaveos.web.cern.ch/hflav-eos/charm/cp\_asym/charm\_asymcp\_19Sep19.html*
- 18 Using  $D^0 \rightarrow K^+K^-$  as the control sample will make the analysis much simpler and will reduce the systematic uncerainty.

# **Methodology**

Time integrated A<sub>CP</sub> is defined as: 
$$
A_{CP} = \frac{\Gamma(D^0 \to K_S^0 K_S^0) - \Gamma(D^0 \to K_S^0 K_S^0)}{\Gamma(D^0 \to K_S^0 K_S^0) + \Gamma(D^0 \to K_S^0 K_S^0)} \quad \Gamma = \text{partial decay width}
$$

Experimentally measured quantity is raw assymetry  $(A_{raw})$  defined as:

$$
A_{raw} \equiv \frac{N(D^0) - N(\overline{D}^0)}{N(D^0) + N(\overline{D}^0)}
$$
  $N(D^0) = measured yield of D^{*+} \rightarrow D^0 \pi^+, D^0 \rightarrow K_s K_s decays$   
  $N(\overline{D}^0) = measured yield of D^{*-} \rightarrow D^0 \pi^-, \overline{D}^0 \rightarrow K_s K_s decays$ 

$$
A_{raw} \approx A_{FB}^{D^{*+}} + A_{CP} + A_{\epsilon}^{\pi_s} (relation between A_{CP} & A_{raw})
$$
\n
$$
A_{raw}^{K_s K_s} = A_{FB}^{D^{*+}} + A_{CP}^{K_s K_s} + A_{\epsilon}^{\pi_s} \rightarrow (i)
$$
\n
$$
A_{raw}^{KK} = A_{FB}^{D^{*+}} + A_{CP}^{KK} + A_{\epsilon}^{\pi_s} \rightarrow (ii)
$$
\n
$$
A_{CP}^{K_s K_s} = (A_{raw}^{K_s K_s} - A_{raw}^{KK}) + A_{CP}^{KK}
$$

*A*ε <sup>π</sup>*s*=*assymetry of the detection efficiency of the slow pion AFB* = *forward backward assymetry*